

Qualcomm Technologies, Inc.

Samsung portable handset (FCC ID: A3LSMG986U) RF Exposure Compliance Test Report_Appendix E: Test Setup Photo

(Part 2: Test Under Dynamic Transmission Condition)

80-W5681-4 Rev. B Appendix E

January 15, 2020

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1 Introduction

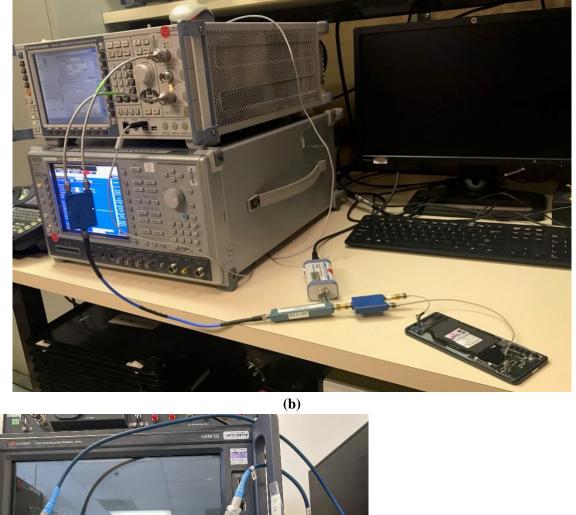
Appendix E is created to include all photos of test setups used in Part 2 compliance test. All photos were taken with actual equipment under test (EUT) of Samsung portable handset (FCC ID: A3LSMG986U).

2 Test Setup Photos with EUT

The photos below are Figures 6-1(a), (b) and (e) in Section 6.1 of Part 2 report, showing conducted power test setup taken with actual EUT.



(a)



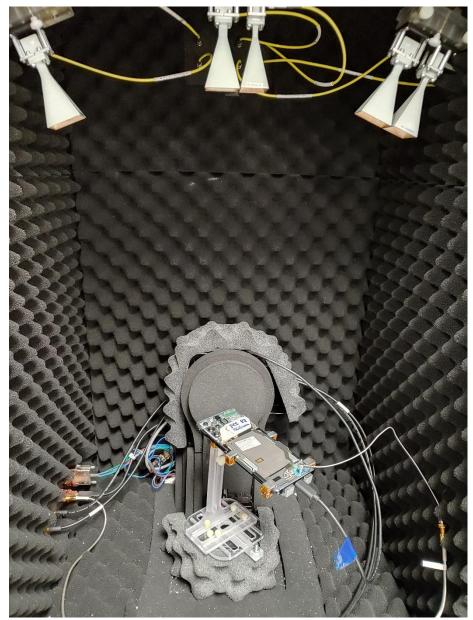


(f) Figure 6-1 Conducted power measurement setup

The photo below is Figure 7-1 in Section 7.1 of Part 2 report, showing SAR measurement setup taken with actual EUT.



Figure 7-1 SAR measurement setup



The photo below is Figure 8-1(a) in Section 8.1 of Part 2 report, showing radiated measurement setup taken with actual EUT.

(a)

Figure 8-1 mmW NR radiated power measurement setup

The photo below is Figure 9-1 in Section 9.1 of Part 2 report, showing PD measurement setup taken with actual EUT.

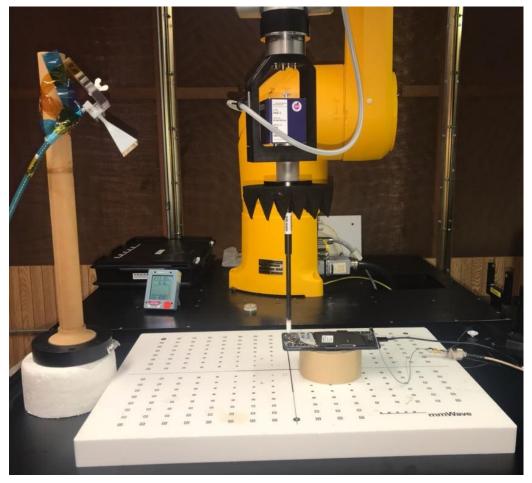


Figure 9-1 Worst-surface of EUT positioned facing up for the mmW beam being tested